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Subclass	ISSUE CLASSIFICATION
Class	

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PATENT NUMBER

U.S. UTILITY Patent Application

JC-3
JC900

O.I.P.E.	PATENT DATE
SCANNED AG 2800 MH	

APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER
09/995680	D F	324	769	~~2818~~ 2829	KARLSEN, E

APPLICANTS: Ha Kim

TITLE: TDDB test pattern and method for testing TDDB of MOS capacitor dielectric

PTO-2040
12/99

ISSUING CLASSIFICATION

ORIGINAL		CROSS REFERENCE(S)	
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)

INTERNATIONAL CLASSIFICATION

☐ Continued on Issue Slip Inside File Jacket

☐ TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
☐ The term of this patent subsequent to _____ (date) has been disclaimed.	(Assistant Examiner) (Date)			NOTICE OF ALLOWANCE MAILED	
☐ The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____	(Primary Examiner) (Date)			ISSUE FEE: Amount Due / Date Paid	
☐ The terminal ____months of this patent have been disclaimed.	(Legal Instruments Examiner) (Date)			ISSUE BATCH NUMBER	

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